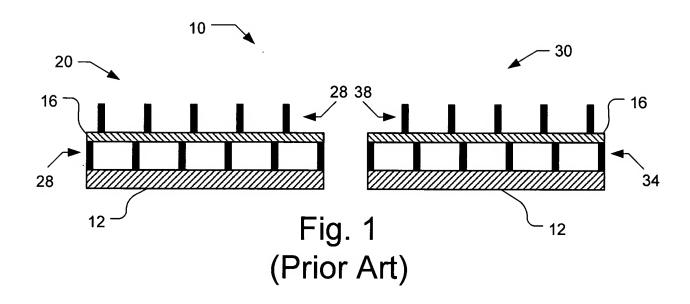
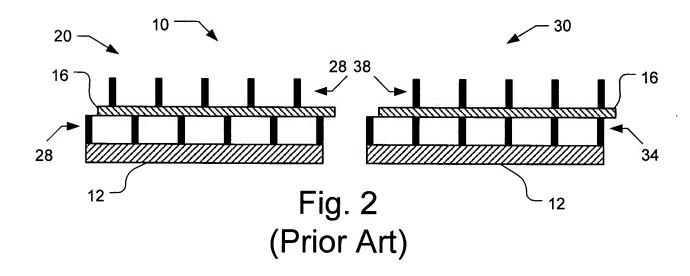
Title: Local Process Variation Correction for Overlay Measurement First Inventor: Weidong Yang Docket Number: NAN066 US 1/5





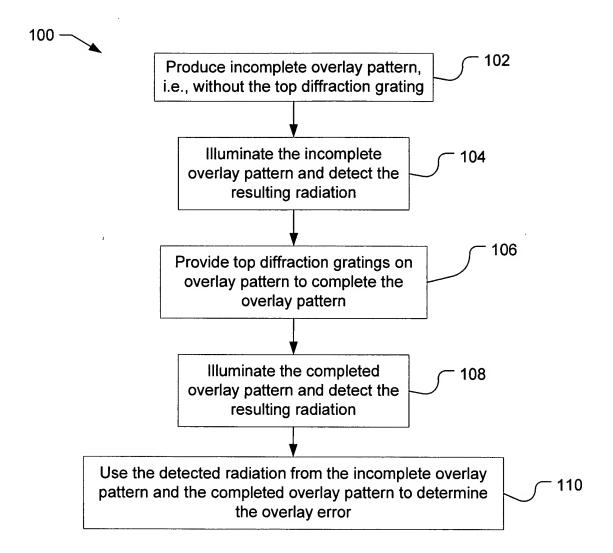


Fig. 3

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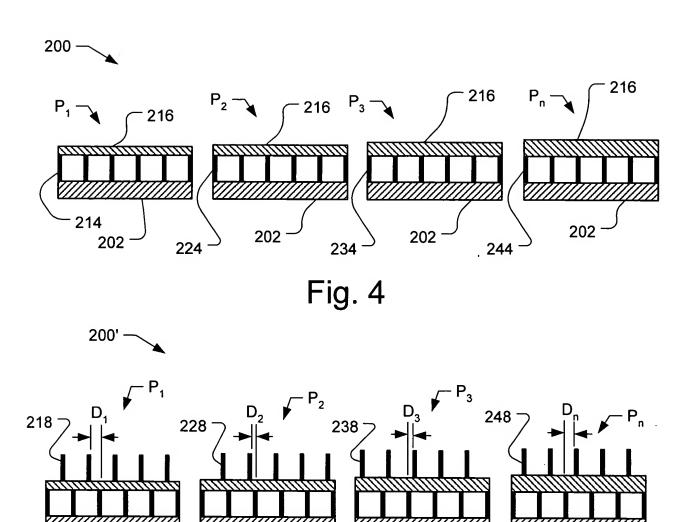


Fig. 6

Title: Local Process Variation Correction for Overlay Measurement First Inventor: Weidong Yang Docket Number: NAN066 US 4/5

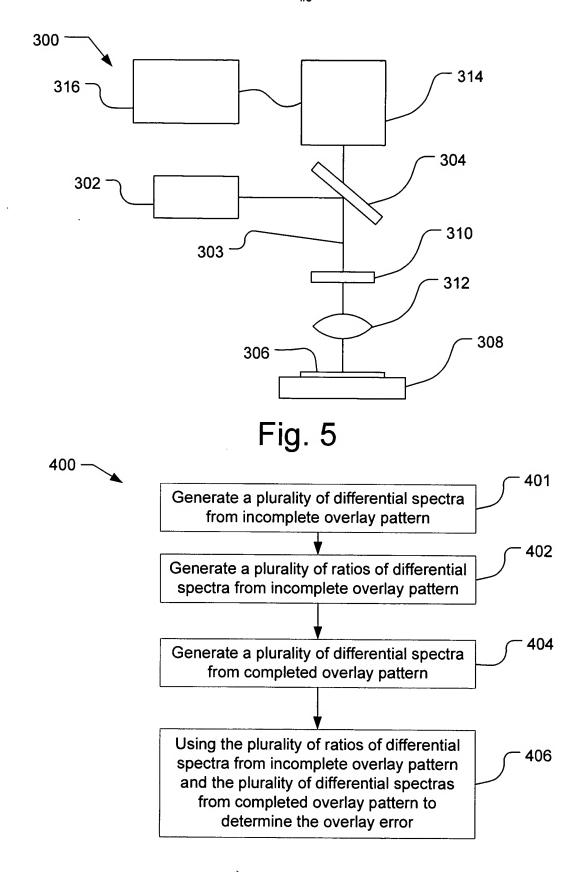


Fig. 7

Title: Local Process Variation Correction for Overlay Measurement First Inventor: Weidong Yang Docket Number: NAN066 US 5/5

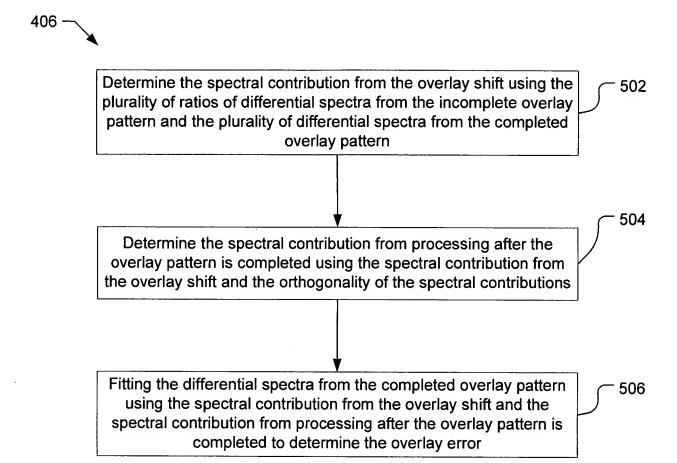


Fig. 8